

CFast 3SE

Customer: _____

Customer

Part

Number: _____

Innodisk

Part

Number: _____

Innodisk

Model Name: _____

Date: _____

Innodisk Approver	Customer Approver

Total Solution For
Industrial Flash Storage

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REVISION HISTORY

Revision	Description	Date
Preliminary	First Released	June, 2013
1.0	Official Released	July, 2013
1.1	Add 02GB	September, 2013

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1. Product Overview

1.1 Introduction of Innodisk CFast 3SE

The Innodisk CFast 3SE operates at SATA III 6.0 Gb/s, which offers data transfer rate of read up to 470MB/sec. and of sequential write up to 250MB/s. Compliant with CFast 2.0 standard, it is designed with 7+17 pin connector and is SATA compatible. Due to the idle power saving, it reduces 35% power consumption. CFast 3SE is featured as small form factor, and suitable for most industrial application.

CFast 3SE can work under harsh environment, and complies with ATA protocol. Without additional driver, the disk can be configured as a boot device or data storage device. CFast 3SE support hardware write protect to prevent modification of valuable data on a device. Besides, through Innodisk's enhanced power cycling technology and more capacitors, CFast 3SE prevents data loss caused by sudden power failure. By using Innodisk's iSMART, users can not only monitor the operation status of SSD, but also visualize Wear-Leveling status with graphics.

1.2 Product View and Models

Innodisk CFast 3SE is available in follow capacities within SLC flash ICs.

CFast 3SE 02GB	CFast 3SE 04GB
CFast 3SE 08GB	CFast 3SE 16GB
CFast 3SE 32GB	CFast 3SE 64GB



Figure 1: Innodisk CFast 3SE

1.3 SATA Interface

Innodisk CFast 3SE supports SATA III interface, and compliant with SATA I and SATA II. SATA III interface can work with Serial Attached SCSI (SAS) host system, which is used in server computer. Innodisk CFast 3SE is compliant with Serial ATA Gen 1, Gen 2 and Gen 3 specification (Gen 3 supports 1.5Gbps /3.0Gbps/6.0Gbps data rate).

1.4 CFast 2.0 Form Factor

CFast 3SE compliant with CFast 2.0 standard, it is designed with 7+17 pin connector and is SATA compatible. CFast 2.0 leverage the same connector interface as CFast 1.1 and the SATA-3 interface for higher performance. CFast 3SE mechanical dimensions : 42.8mm x 36.4mm x 3.6mm.

2. Product Specifications

2.1 Capacity and Device Parameters

CFast 3SE device parameters are shown in Table 1.

Table 1: Device parameters

Capacity	LBA	Cylinders	Heads	Sectors	User Capacity(MB)
02GB	3928176	3897	16	63	1918
04GB	7835184	7773	16	63	3825
08GB	15649200	15525	16	63	7641
16GB	31277232	16383	16	63	15272
32GB	62533296	16383	16	63	30533
64GB	125045424	16383	16	63	61057

2.2 Performance

Burst Transfer Rate: 6.0Gbps

Table 2: Performance

Capacity	02GB	04GB	08GB	16GB	32GB	64GB
Sequential Read (max.)	50MB/s	220 MB/s	360 MB/s	440 MB/s	470 MB/s	470 MB/s
Sequential Write (max.)	27MB/s	60 MB/s	110 MB/s	130 MB/s	250 MB/s	250 MB/s

Note: Base on CrystalDiskMark 3.01 with file size 1000MB

2.3 Electrical Specifications

2.3.1 Power Requirement

Table 3: Innodisk CFast 3SE Power Requirement

Item	Symbol	Rating	Unit
Input voltage	V _{IN}	+3.3 DC +- 5%	V

2.3.2 Power Consumption

Table 4: Power Consumption

Mode	Power Consumption (mA)
Read	240 (max.)
Write	320 (max.)
Idle	110 (max.)

2.4 Environmental Specifications

2.4.1 Temperature Ranges

Table 5: Temperature range for CFast 3SE

Temperature	Range
Operating	Standard Grade: 0°C to +70°C
	Industrial Grade: -40°C to +85°C
Storage	-55°C to +95°C

2.4.2 Humidity

Relative Humidity: 10-95%, non-condensing

2.4.3 Shock and Vibration

Table 6: Shock/Vibration Testing for CFast 3SE

Reliability	Test Conditions	Reference Standards
Vibration	7 Hz to 2K Hz, 20G, 3 axes	IEC 68-2-6
Mechanical Shock	Duration: 0.5ms, 1500 G, 3 axes	IEC 68-2-27

2.4.4 Mean Time between Failures (MTBF)

Table 7 summarizes the MTBF prediction results for various CFast 3SE configurations. The analysis was performed using a RAM Commander™ failure rate prediction.

- **Failure Rate:** The total number of failures within an item population, divided by the total number of life units expended by that population, during a particular measurement interval under stated condition.
- **Mean Time between Failures (MTBF):** A basic measure of reliability for repairable items: The mean number of life units during which all parts of the item perform within their specified limits, during a particular measurement interval under stated conditions.

Table 7: CFast 3SE MTBF

Product	Condition	MTBF (Hours)
Innodisk CFast 3SE	Telcordia SR-332 GB, 25°C	>3,000,000

2.5 CE and FCC Compatibility

CFast 3SE conforms to CE and FCC requirements.

2.6 RoHS Compliance

CFast 3SE is fully compliant with RoHS directive.

2.7 Reliability

Parameter	Value
Read Cycles	Unlimited Read Cycles
Wear-Leveling Algorithm	Support
Bad Blocks Management	Support
Error Correct Code	Support
Flash endurance	100,000 P/E cycles
TBW(Sequential Write)	
02GB	180
04GB	360
08GB	720
16GB	1440
32GB	2880
64GB	5760

2.8 Transfer Mode

CFast 3SE support following transfer mode:

Serial ATA III 6.0Gbps

Serial ATA II 3.0Gbps

Serial ATA I 1.5Gbps

2.9 Pin Assignment

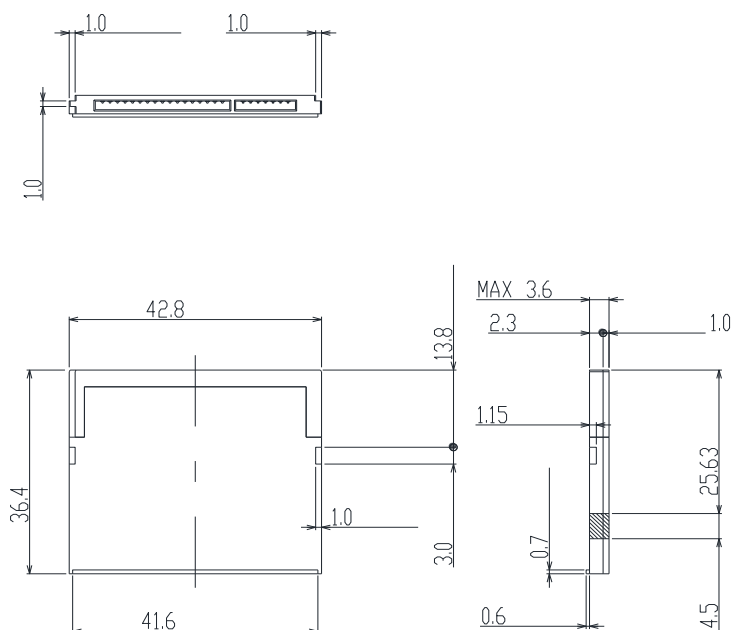
Innodisk CFast 3SE uses a standard SATA pin-out. See Table 8 for CFast 3SE pin assignment.

Table 8: Innodisk CFast 3SE Pin Assignment

Name	Type	Description
S1	SGND	Ground for signal integrity
S2	A+	Differential Signal Pair A
S3	A-	
S4	SGND	Ground for signal integrity
S5	B-	Differential Signal Pair B
S6	B+	
S7	SGND	Ground for signal integrity
Key and Spacing separate signal and power segments		

P1	CDI	Card Detect In
P2	PGND	Device Ground
P3	DEVSLP	Device sleep
P4	TBD	Reserved
P5	TBD	Reserved
P6	TBD	Reserved
P7	PGND	Device Ground
P8	LED1	LED Output
P9	LED2	LED Output
P10	TBD	Reserved
P11	TBD	Reserved
P12	IFDet	NA
P13	PWR	Device Power (3.3V)
P14	PWR	Device Power (3.3V)
P15	PGND	Device Ground
P16	PGND	Device Ground
P17	CDO	Card Detect Out

2.10 Mechanical Dimensions



2.11 Assembly Weight

An InnodiskCFast 3SE within SLC flash ICs, 64GB's weight is 8 grams approx. The total weight of card will be less than 10 grams.

2.12 Seek Time

Innodisk CFast 3SE is not a magnetic rotating design. There is no seek or rotational latency required.

2.13 Hot Plug

The card support hot plug function and can be removed or plugged-in during operation. User has to avoid hot plugging the card which is configured as boot device and installed operation system.

Surprise hot plug : The insertion of a SATA device into a backplane (combine signal and power) that has power present. The device powers up and initiates an OOB sequence.

Surprise hot removal: The removal of a SATA device from a powered backplane, without first being placed in a quiescent state.

2.14 NAND Flash Memory

Innodisk CFast 3SE uses single Level Cell (SLC) NAND flash memory, which is non-volatility, memory storage. There are two statuses 0 or 1 of one cell. Read or Write data to flash memory for SSD is control by microprocessor.

3. Theory of Operation

3.1 Overview

Figure 2 shows the operation of Innodisk CFast 3SE from the system level, including the major hardware blocks.

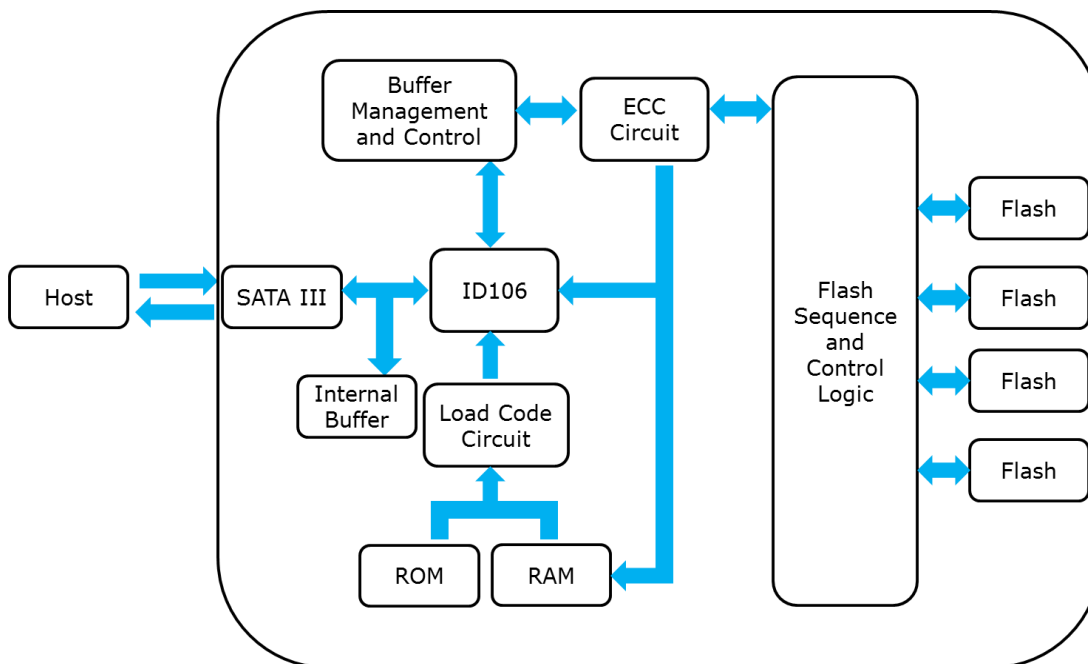


Figure 2: Innodisk CFast 3SE Block Diagram

Innodisk CFast 3SE integrates a SATA III controller and NAND flash memories. Communication with the host occurs through the host interface, using the standard ATA protocol. Communication with the flash device(s) occurs through the flash interface.

3.2 SATA III Controller

Innodisk CFast 3SE is designed with ID 106, a SATA III 6.0Gbps (Gen. 3) controller. The Serial ATA physical, link and transport layers are compliant with Serial ATA Gen 1, Gen 2 and Gen 3 specification (Gen 3 supports 1.5Gbps/3.0Gbps/6.0Gbps data rate). The controller has 4 channels for flash interface.

3.3 Error Detection and Correction

Highly sophisticated Error Correction Code algorithms are implemented. The ECC unit consists of the Parity Unit (parity-byte generation) and the Syndrome Unit (syndrome-byte computation). This unit implements an algorithm that can correct 40 bits per 1024 bytes in an ECC block. Code-byte generation during write operations, as well as error detection during read operation, is implemented on the fly without any speed penalties.

3.4 Wear-Leveling

Flash memory can be erased within a limited number of times. This number is called the **erase cycle limit** or **write endurance limit** and is defined by the flash array vendor. The erase cycle limit applies to each individual erase block in the flash device.

Innodisk CFast 3SE uses a static wear-leveling algorithm to ensure that consecutive writes of a specific sector are not written physically to the same page/block in the flash. This spreads flash media usage evenly across all pages, thereby extending flash lifetime.

3.5 Bad Blocks Management

Bad Blocks are blocks that contain one or more invalid bits whose reliability are not guaranteed. The Bad Blocks may be presented while the SSD is shipped, or may develop during the life time of the SSD. When the Bad Blocks is detected, it will be flagged, and not be used anymore. The SSD implement Bad Blocks management, Bad Blocks replacement, Error Correct Code to avoid data error occurred. The functions will be enabled automatically to transfer data from Bad Blocks to spare blocks, and correct error bit.

3.6 Power Cycling

Innodisk's power cycling management is a comprehensive data protection mechanism that functions before and after a sudden power outage to SSD. Low-power detection terminates data writing before an abnormal power-off, while table-remapping after power-on deletes corrupt data and maintains data integrity. Innodisk's power cycling provides effective power cycling management, preventing data stored in flash from degrading with use.

3.7 Garbage Collection

Garbage collection technology is used to maintain data consistency and perform continual data cleansing on SSDs. It runs as a background process, freeing up valuable controller resources while sorting good data into available blocks, and deleting bad blocks.

4. Installation Requirements

4.1 CFast 3SE Pin Directions

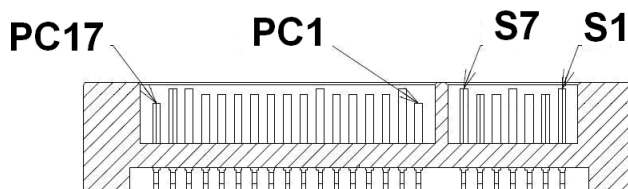
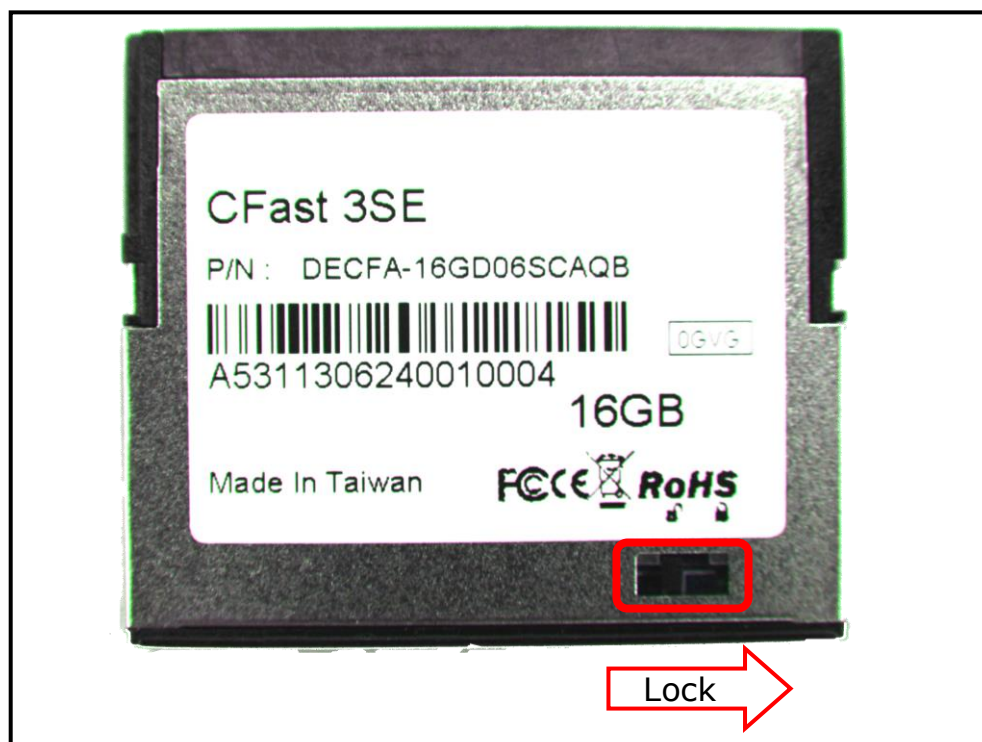


Figure 3: Signal Segment and Power Segment

4.2 Electrical Connections for CFast 3SE

A Serial ATA device may be either directly connected to a host or connected to a host through a cable. For connection via cable, the cable should be no longer than 1meter. The SATA interface has a separate connector for the power supply. Please refer to the pin description for further details.

4.3 Write Protection



Innodisk CFast 3SE within the write-protect function could prevent the device from modification and deletion. Write-protected data could only be read, that is, users could not write to it, edit it, append data to it, or delete it. When users would like to make sure that neither themselves nor others could modify or destroy the file, users could switch on write-protection. Thus, Innodisk CFast 3SE could process write-protect mechanism and disable flash memory to be written-in any data. Only while the system power-off, users could switch on write-protection. Write-protection could not be switched-on, after OS booting.

4.4 Device Drive

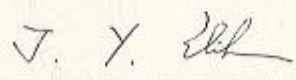
No additional device drives are required. Innodisk CFast 3SE can be configured as a boot device.

5. Part Number Rule

CODE	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21
	D	E	C	F	A	-	3	2	G	D	0	6	S	C	1	Q	B	-	X	X	X
Description	Disk	CFast 3SE					Capacity			Controller			Flash Mode	Operation Temp.	Internal Control	CH.	Flash Type	-	Customized Code		
Definition																					
Code 1 st (Disk)												Code 13 th (Flash Mode)									
D : Disk												S: Synchronous flash									
												A: Asynchronous flash									
Code 2 nd ~ 5 th (Form Factor)												Code 14 th (Operation Temperature)									
ECFA: CFast 3SE												C: Standard Grade (0℃ ~ +70℃)									
Code 7 th ~9 th (Capacity)												W: Industrial Grade (-40℃ ~ +85℃)									
02G: 02GB												Code 15 th (Internal control)									
04G: 04GB												A: BGA PCB version									
08G: 08GB												1: TSOP PCB version									
16G: 16GB												Code 16 th (Channel of data transfer)									
32G: 32GB												D: Dual Channels									
64G: 64GB												Q: Four Channels									
												Code 17 th (Flash Type)									
												B: Toshiba SLC									
Code 10 th ~12 th (Controller)												Code 19 th ~21 th (Customized Code)									
D06: ID106																					
D07: ID107																					

Appendix

CE/FCC/RoHS (TBD)

Verification of Compliance	
Product Name	: CFast 3SE
Model Number	: DECFA-XXXD06 * # % ※ & XXX: 1GB~64GB * : Flash Mode # : Temperature (C : Commercial Temp W : Industrial Temp E: Extended Temp) % : PCB Version (A, B, C... or 1, 2, 3...) ※ : Channel (S : Single, D : Dual, Q : Quad, E : Eight) & : Flash Vender (S: Samsung SLC, T: Micron SLC, B: Toshiba SLC, C:Toshiba MLC, F: Sandisk SLC, X: SLC, M:Samsung MLC, N: Micron MLC)
Applicant	: Innodisk Corporation
Address	: 9F, No.100, Sec. 1, Xintai 5th Rd., Xizhi Dist., New Taipei City 221, Taiwan
Report Number	: F-U070-1307-317
Issue Date	: August 8, 2013
Applicable Standards	: FCC Part 15, Subpart B Class B ITE ANSI C63.4:2009 Industry Canada ICES-003 Issue 5 CSA-IEC CISPR22-10 Class B ITE
One sample of the designated product has been tested in our laboratory and found to be in compliance with the FCC rules cited above.	
  NVLAP LAB CODE 200575-0 TAF 0905 FCC CAB Code TW1053 IC Code 4699A VCCI Accep. No. R-1527, C-1609, T-1441, G-10, C-4400, T-1334, G-614  Central Research Technology Co. EMC Test Laboratory 11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C. Tel : 886-2-25984568 Fax: 886-2-25984546	
 (Tsun-Yu Shih/ General Manager) Date: <u>August 8, 2013</u>	

Verification of Compliance

Product Name : CFast 3SE
 Model Number : DECFA-XXXD06 * # % ※ &
 XXX: 1GB~64GB
 * : Flash Mode
 # : Temperature (C : Commercial Temp W : Industrial Temp
 E: Extended Temp)
 % : PCB Version (A, B, C..., or 1, 2, 3...)
 ※ : Channel (S : Single, D : Dual, Q : Quad, E : Eight)
 & : Flash Vender (S: Samsung SLC, T: Micron SLC,
 B: Toshiba SLC, C: Toshiba MLC, F: Sandisk SLC, X: SLC,
 M: Samsung MLC, N: Micron MLC)
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 Address : 9F, No.100, Sec. 1, Xintai 5th Rd., Xizhi Dist., New Taipei City 221,
 Taiwan
 Report Number : O22-U070-1307-317
 Issue Date : August 8, 2013
 Applicable Standards : EN 55022:2010 Class B ITE
 AS/NZS CISPR22:2009 Class B ITE
 EN 55024:2010
 EN 61000-4-2:2009
 EN 61000-4-3:2006+A1:2008+A2:2010
 EN 61000-4-4:2004+A1:2010

Based on the EMC Directive 2004/108/EC and the specifications of the customer, one sample of the designated product has been tested in our laboratory and found to be in compliance with the EMC standards cited above.



TAF 0905
 FCC CAB Code TW1053
 NVLAP Lab Code 200575-0
 IC Code 4699A
 VCCI Accep. No. R-1527, C-1609, T-1441, G-10,
 C-4400, T-1334, G-614



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J. Y. Shih

(Tsun-Yu Shih/ General Manager)

Date: August 8, 2013